

Supporting Information

Optimizing thermoelectric properties through compositional engineering in Ag-deficient AgSbTe₂ synthesized by arc melting

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SI1. Differential Scanning Calorimetry (DSC)

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SI1. Differential Scanning Calorimetry (DSC)

Figure S1 shows the Differential scanning calorimetry (DSC) curves for the $\text{Ag}_{0.7}\text{Sb}_{1.12}\text{Te}_2$ and $\text{Ag}_{0.7}\text{Sb}_{1.12}\text{Te}_{1.95}\text{Se}_{0.05}$.

A signal around 418 K has been reported in Ag_2Te , associated with the monoclinic to cubic phase transition, that it is not present in our samples (Cao, J et al (2023). *Nano Energy*, 107, 108118). DSC results confirms that there is no Ag_2Te impurity in the arc-melting samples, as it was observed by synchrotron X-ray diffraction).

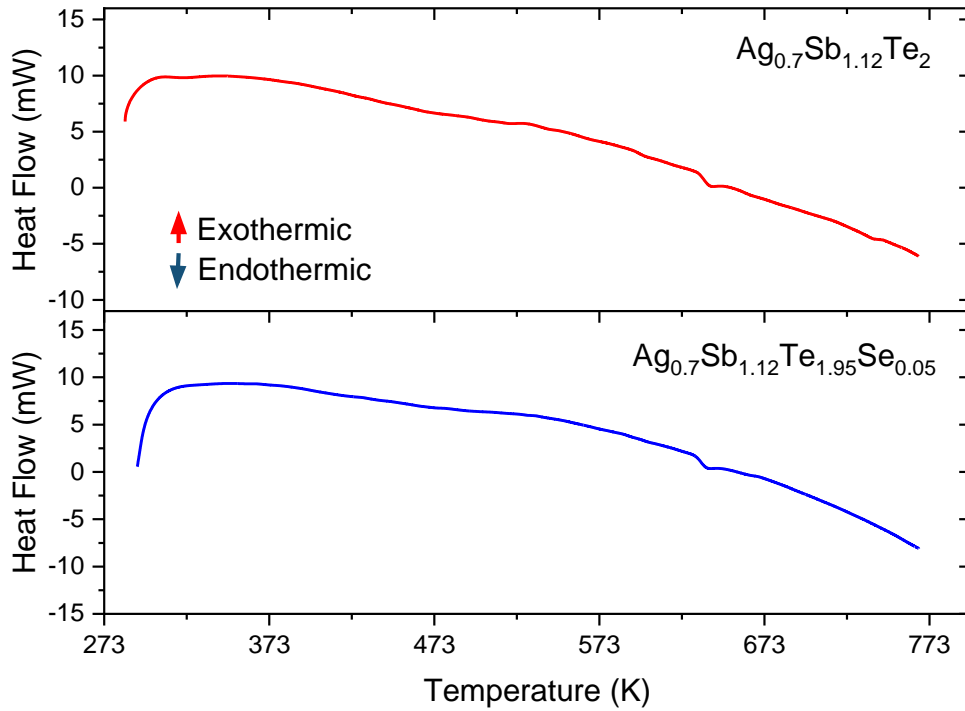
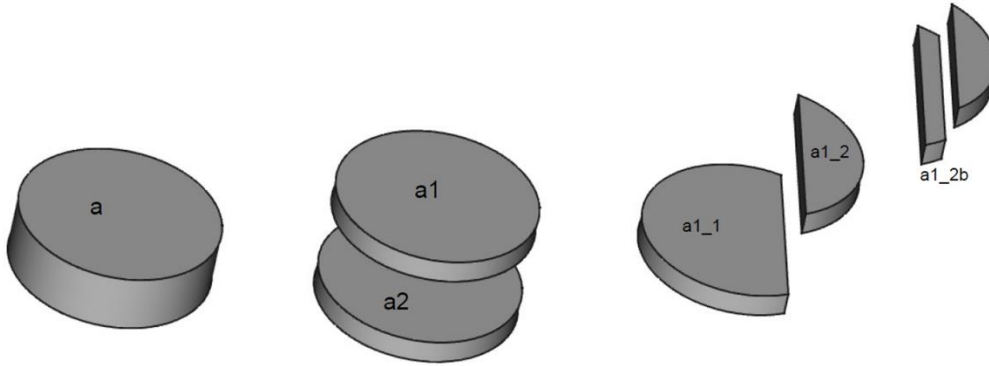


Figure S1. Differential scanning calorimetry (DSC) curves for the $\text{Ag}_{0.7}\text{Sb}_{1.12}\text{Te}_2$ and $\text{Ag}_{0.7}\text{Sb}_{1.12}\text{Te}_{1.95}\text{Se}_{0.05}$.

S12. Sample cutting process

(a)



Original sintered pellet (a)

(a) is cut along its section (cut along the in-plane direction). Thus, two similar discs are obtained (a1 and a2). Thermal diffusivity is measured in a2.

One cut perpendicular to the in-plane direction in a1 yields two symmetrical pieces, denoted as a1_1 and a1_2. The resistivity (by van der Pauw method) is measured in a1_1, while a1_2 is further cut into a bar, labeled as a1_2b (and another unused piece). The Seebeck coefficient is measured in a1_2b.

(b)

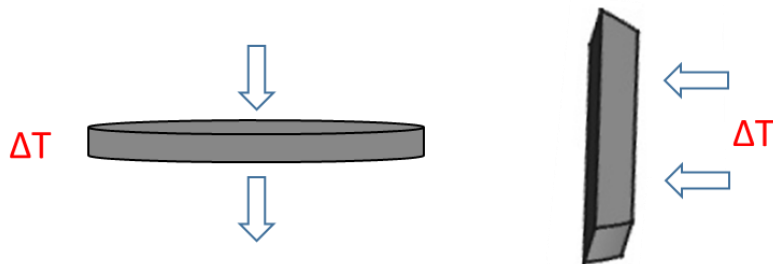


Figure S2. (a) Diagram illustrating how the different sections of the sample were cut for thermoelectric measurements. (b) ΔT and current direction in thermal diffusivity (pellet) and Seebeck coefficient (bar) measurements.

S13. EDX analysis

The composition has been assessed semi-quantitatively using Energy Dispersive X-ray Spectroscopy (EDX) on more than ten individual crystals for each sample. Here, we show the average % atomic values in order to compare with the formula achieved by Rietveld refinement of the synchrotron X-ray diffraction data.

1) Rietveld refinement formula: $\text{Ag}_{0.86(4)}\text{Sb}_{1.06(4)}\text{Te}_{1.93(1)}$

EDX analysis: $\text{Ag}_{0.9}\text{Sb}_{1.04}\text{Te}_2$

Table S1 EDX results in nominal $\text{Ag}_{0.7}\text{Sb}_{1.12}\text{Te}_2$:

Element	% atomic
Ag	20.27
Sb	26.44
Te	53.29

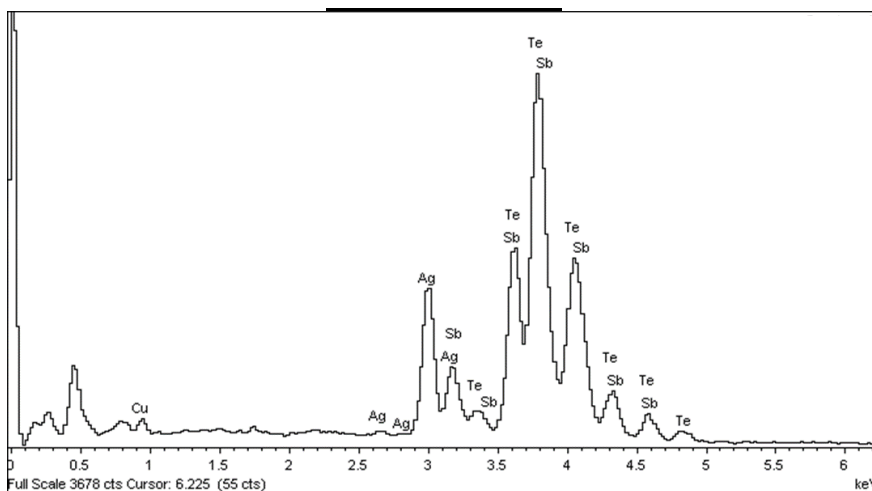


Figure S3. EDX spectra of nominal $\text{Ag}_{0.7}\text{Sb}_{1.12}\text{Te}_2$

2) Rietveld refinement analysis: $\text{Ag}_{0.8}\text{Sb}_{1.14}\text{Te}_{1.91}\text{Se}_{0.09}$ + $\text{Ag}_{0.8}\text{Sb}_{1.14}\text{Te}_{1.97}\text{Se}_{0.03}$ (phase segregation)

EDX analysis: $\text{Ag}_{0.79}\text{Sb}_{1.13}\text{Te}_{1.87}\text{Se}_{0.06}$

Table S2. EDX results in nominal $\text{Ag}_{0.7}\text{Sb}_{1.12}\text{Te}_{1.95}\text{Se}_{0.05}$

Element	% atomic
Ag	18.28
Sb	29.52
Te	51.19
Se	1.01

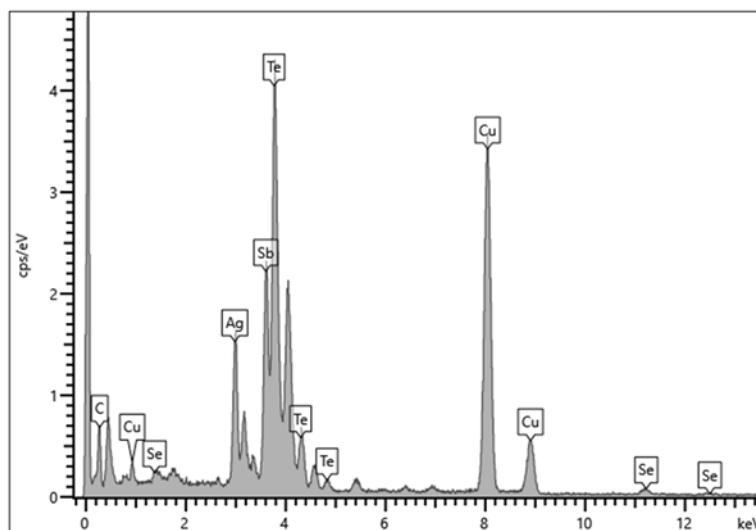


Figure S4. EDX spectra of nominal $\text{Ag}_{0.7}\text{Sb}_{1.12}\text{Te}_{1.95}\text{Se}_{0.05}$

SI4. Atomic displacement parameters of nominal AgSbTe₂

Table S3. Result of Atomic displacement parameters (ADP) of nominal AgSbTe₂, adapted from ref [J. Gainza et al. *Nanomaterials* **2022**, 12 (21), 3910].

<i>Atomic Displacement Parameters (Å²)</i>					
	<i>U¹¹</i>	<i>U²²</i>	<i>U³³</i>	<i>U¹²</i>	<i>U¹³</i>
<i>Te1</i>	0.022 (5)	0.04 (1)	0.022 (5)	0.00000	0.00000
<i>Sb</i>	0.038 (8)	0.038 (8)	0.038 (8)	0.00000	0.00000
<i>Ag</i>	0.036 (5)	0.036 (5)	0.005 (6)	0.00000	0.00000
<i>Sb2</i>	0.036 (5)	0.036 (5)	0.005 (6)	0.00000	0.00000

SI5. Hall carrier concentration and mobility

Table S4. Hall carrier concentration and mobility at T=300 K of the arc-melted samples.

Nominal Composition	n_H (cm ⁻³)	μ_n (cm ² V ⁻¹ s ⁻¹)	p_H (cm ⁻³)	μ_p (cm ² V ⁻¹ s ⁻¹)
Ag _{0.7} Sb _{1.12} Te ₂	3.7×10^{17}	64	1.5×10^{20}	2.5
Ag _{0.7} Sb _{1.12} Te _{1.95} Se _{0.05}	1.5×10^{16}	83	5.7×10^{19}	1.4

SI6. Thermal conductivity

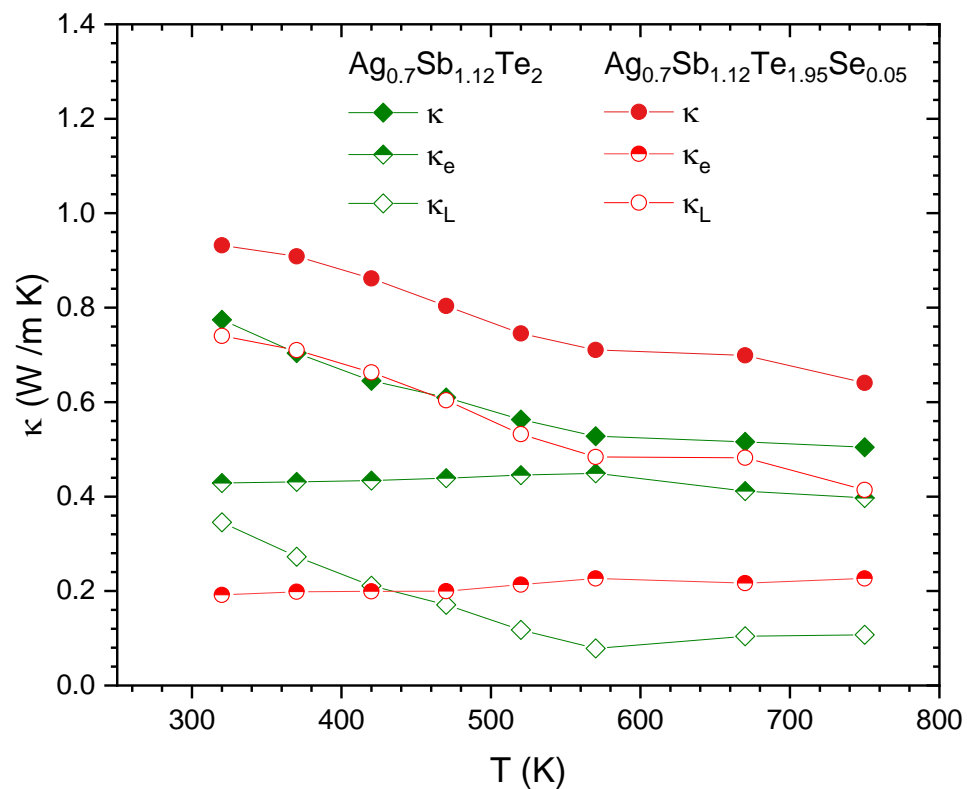


Figure S5 Temperature dependence of the total thermal conductivity and the thermal and electronic contributions of the thermal conductivity.

SI7. Reproducibility study

Two samples have been measured in order to assure the thermoelectric properties of the system.

Figures S6, S7 and S8 shows the temperature dependence of the Seebeck coefficient, electrical conductivity and thermal conductivity.

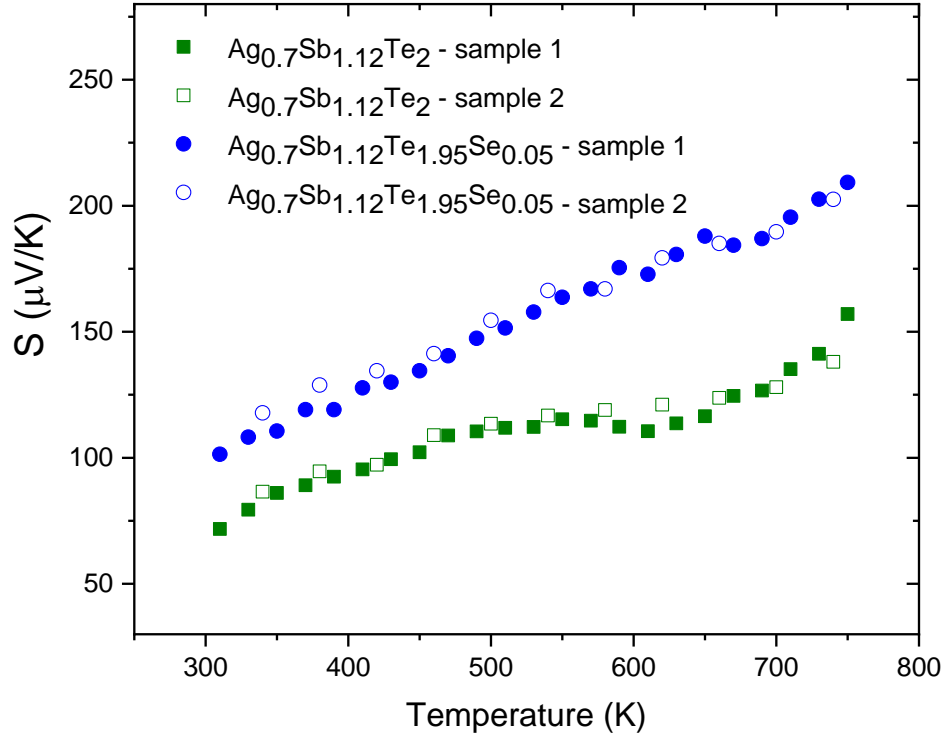


Figure S6. Temperature dependence of the Seebeck coefficient.

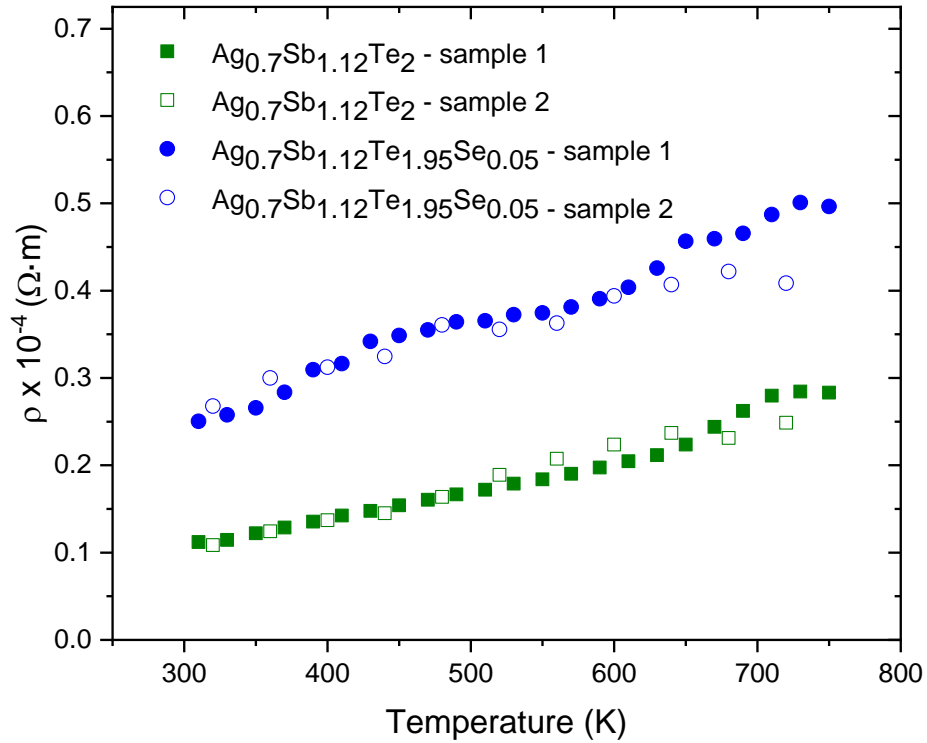


Figure S7. Temperature dependence of the electrical resistivity.

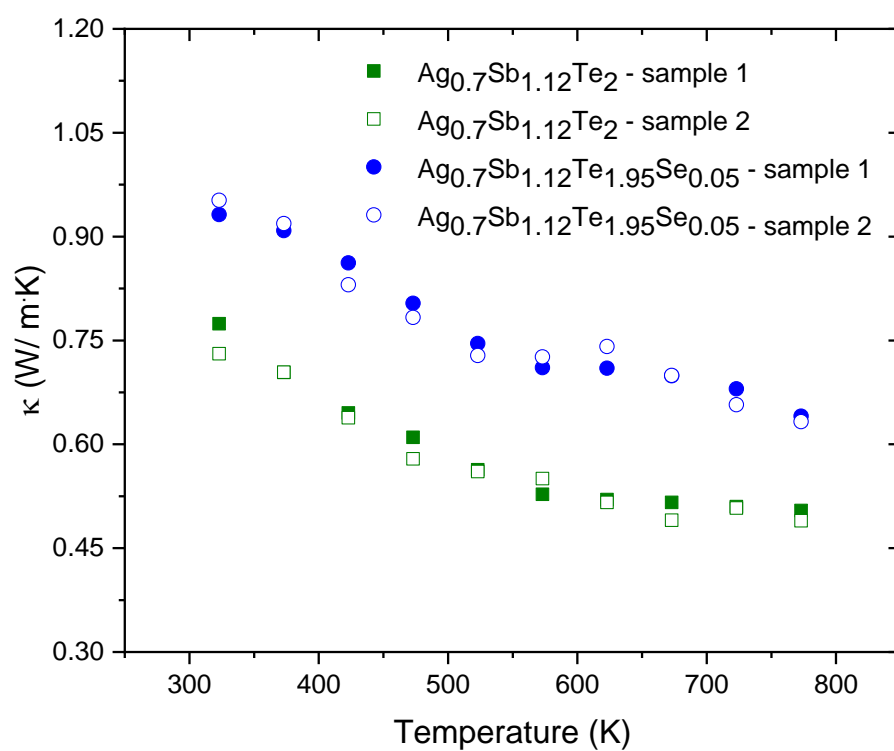


Figure S8. Temperature dependence of the thermal conductivity.